

Notice of References Cited	Application/Control No. 09/770,569	Applicant(s)/Patent Under Reexamination MERKIN ET AL.	
	Examiner Chun Cao	Art Unit 2115	Page 1 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,681,351	01-2004	Kittross et al.	714/724
	C	US-6,654,816	11-2003	Zaudtke et al.	710/1
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	M	US-5,864,698	01-1999	Krau et al.	713/2

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	V	Bukowski et al., "Case Study of a Year 200 Platform Testing Initiative", 1999 PROCEEDINGS Annual RELIABILITY and MAINTAINABILITY Symposium, pp 224-229.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	K	US-			
	L	US-			
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